

RoHS

COMPLIANT

HALOGEN

FREE

Q006-VB Datasheet P-Channel 30 V (D-S) MOSFET

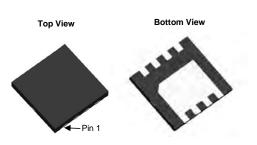
V _{DS}		-30	V
R _{DS(on),typ}	V _{GS} =10V	11	mΩ
R _{DS(on),typ}	V _{GS} =4.5V	18	mΩ
ID	-45	А	

FEATURES

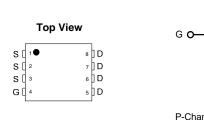
- Halogen-free According to IEC 61249-2-21
 Definition
- Trench Power MOSFET
- Low Thermal Resistance Power
 Package with Small Size and Low 1.07 mm
 Profile
- 100 % $\rm R_g$ and UIS Tested
- Compliant to RoHS Directive 2002/95/EC

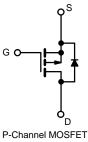
APPLICATIONS

- · Load Switch
- Adaptor Switch
- Notebook PC



DFN 3x3 EP





Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	- 30	V	
Gate-Source Voltage		V _{GS}	± 20	v	
	T _C = 25 °C		- 45		
Continuous Drain Current $(T = 150 ^{\circ}\text{C})$	T _C = 70 °C		- 30		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	- 14.4 ^{a, b}		
	T _A = 70 °C		- 11.5 ^{a, b}	•	
Pulsed Drain Current	I _{DM}	- 60	— A		
	T _C = 25 °C		- 35 ^e		
Continuous Source-Drain Diode Current	T _A = 25 °C	Is	- 3.2 ^{a, b}		
Avalanche Current	L = 0.1 mH	I _{AS}	- 25		
Single-Pulse Avalanche Energy		E _{AS}	31.25	mJ	
	T _C = 25 °C		52		
Maximum Power Discinction	T _C = 70 °C	P _D	43	w	
Maximum Power Dissipation	T _A = 25 °C	'D	3.8 ^{a, b}	v	
	T _A = 70 °C		2.4 ^{a, b}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 50 to 150	°C	
Soldering Recommendations (Peak Temperature) ^{c, d}			260		

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c.Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.

d.Package limited.

e.Based on T $_{\rm C}$ = 25 °C



THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{a, b}	t ≤ 10 s	R _{thJA}	26	33	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.9	2.4	0/00

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. Maximum under Steady State conditions is 81 °C/W.

SPECIFICATIONS (T _J = 25 °C, unless otherwise noted) Parameter Symbol Test Conditions			Min.	Тур.	Max.	Unit	
Static	Cymbol			iyp.	max.	Onic	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$			- 20			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	- 1.5		- 2.8	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
-	000	$V_{\rm DS} = -30 \text{ V}, \text{ V}_{\rm GS} = 0 \text{ V}$			- 1	μΑ	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			- 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 V, V_{GS} = -10 V$	- 20		-	Α	
_		V _{GS} = - 10 V, I _D = - 14.4 A		11			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 11.5 A		18		mΩ	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 14.4 A		37		S	
Dynamic ^b					1	1	
Input Capacitance	C _{iss}			2000		pF	
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		385			
Reverse Transfer Capacitance	C _{rss}			322			
		$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -14.4 \text{ A}$			15	nC	
Total Gate Charge	Qg				14		
Gate-Source Charge	Q _{gs}	V _{DS} = - 15 V, V _{GS} = - 4.5 V, I _D = - 14.4 A			7		
Gate-Drain Charge	Q _{gd}	1			9		
Gate Resistance	R _q	f = 1 MHz	0.4	1.8	3.6	Ω	
Turn-On Delay Time	t _{d(on)}			50	75	-	
Rise Time	t _r	V_{DD} = - 15 V, R _L = 1.5 Ω		43	65		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		30	45		
Fall Time	t _f	1 ř		14	21		
Turn-On Delay Time	t _{d(on)}			14	21	ns	
Rise Time	t _r	V_{DD} = - 15 V, R _L = 1.5 Ω		9	18		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 10 V, R_g = 1 Ω		36	54		
Fall Time	t _f			10	20	1	
Drain-Source Body Diode Characterist	ics	·					
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			- 35 ^e	٩	
Pulse Diode Forward Current ^a	I _{SM}				- 60	A	
Body Diode Voltage	V _{SD}	I _F = - 10 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			31	47	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 10.0 dt/dt = 100.0/m = 0.000		30	45	nC	
Reverse Recovery Fall Time	t _a	$I_F = -10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$		15			
Reverse Recovery Rise Time	t _b			16		ns	

Notes:

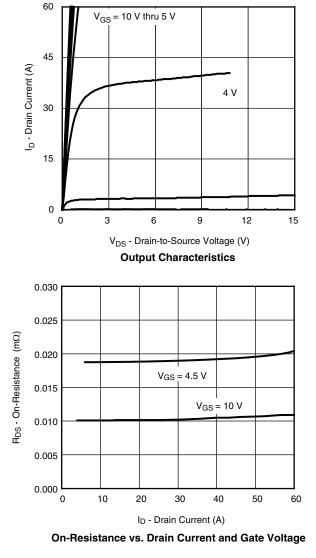
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

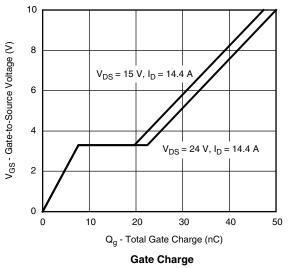
b. Guaranteed by design, not subject to production testing.

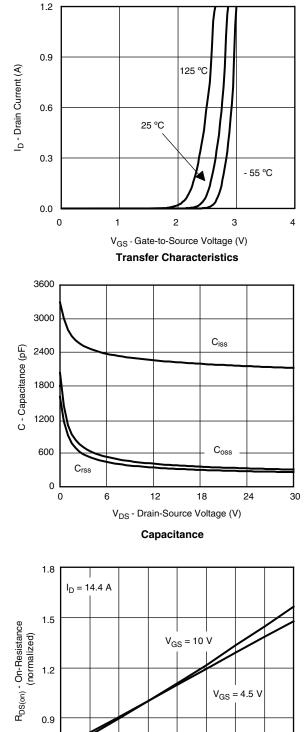
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



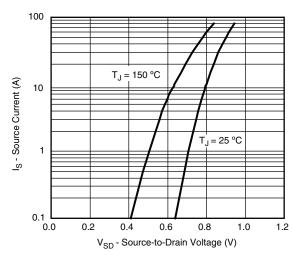






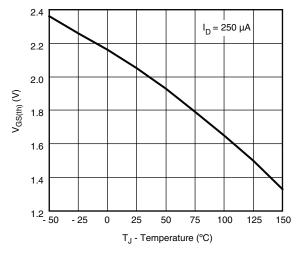




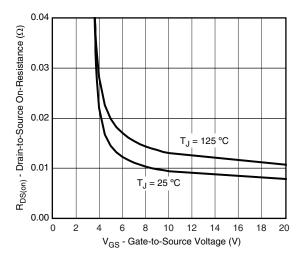


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

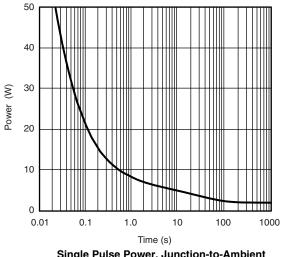




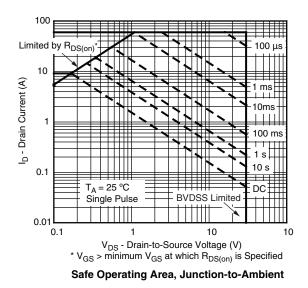
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

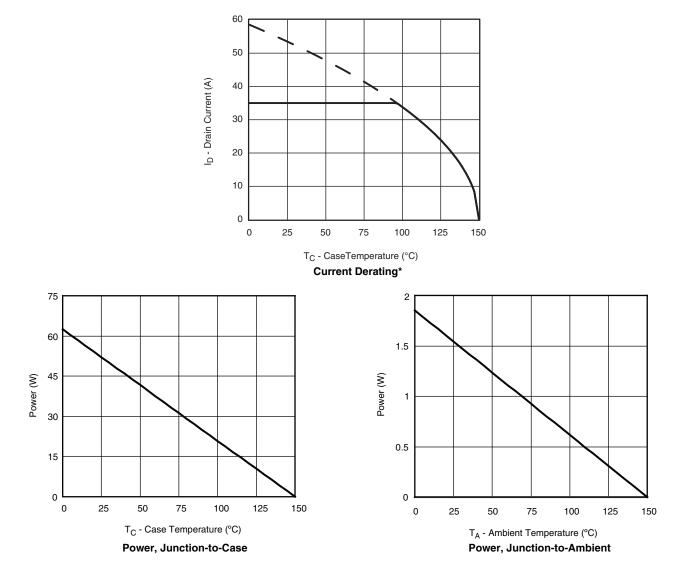


Single Pulse Power, Junction-to-Ambient





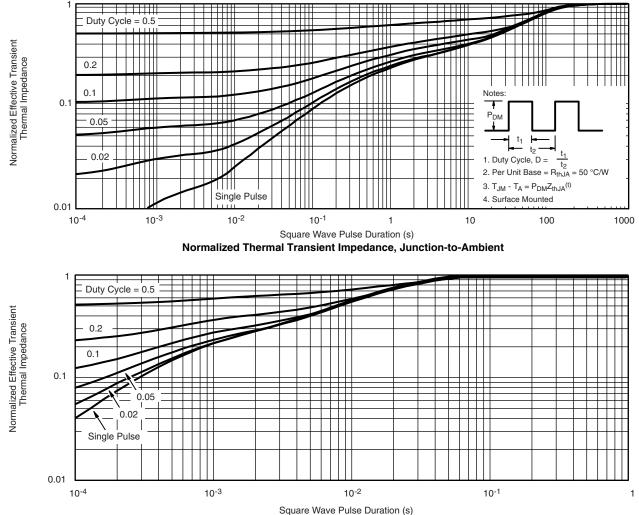
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

1

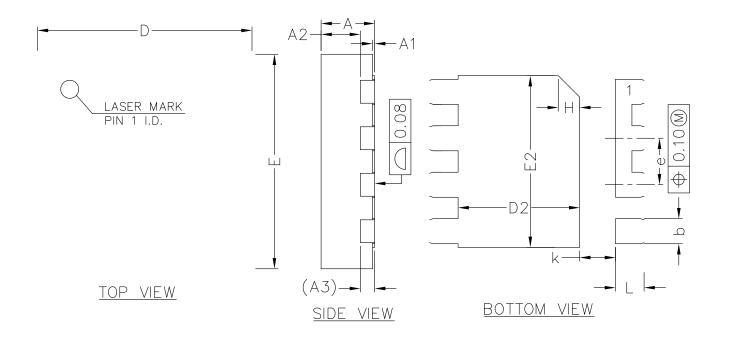




TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Normalized Thermal Transient Impedance, Junction-to-Case

B VBsemi www.VBsemi.com





<u>SIDE VIEW</u>

			,
SYMBOL	MIN	NOM	MAX
А	0.70	0.75	0.80
A1	0.00	0.02	0.05
A2	0.50	0.55	0.60
A3		0.20REF	
b	0.30	0.35	0.40
D	2.90	3.00	3.10
E	2.90	3.00	3.10
D2	1.60	1.70	1.80
E2	2.30	2.40	2.50
е	0.55	0.65	0.75
К	0.40	0.50	0.60
L	0.35	0.40	0.45

COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)



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